SERIES M18 · STANDARDS

Calibration and test specimens



Reference specimens to check magnification, resolution, scanner linearity and step height. Use them for routine instrument verification and after maintenance.

- SEM specimens supplied on pin stubs
- AFM specimens on Ø 12 mm steel discs
- Certificate of measurement on request
- Re-usable when stored clean

CONFIGURATIONS

Ref. No.	Specimen	Feature	Use	Price
M1801	SEM magnification grating	Cross-grating, pitch 0.5 – 10 µm	Magnification and distortion check	On request
M1802	SEM resolution test	Gold particles on carbon	Resolution, astigmatism, focus	On request
M1803	SEM resolution test	Tin spheres on carbon	Resolution, astigmatism, focus	On request
M1804	AFM pitch grating, 1D	Pitch 3 µm	Lateral (X / Y) calibration	On request
M1805	AFM pitch grating, 1D	Pitch 10 µm	Lateral (X / Y) calibration	On request
M1806	AFM pitch grating, 2D	Pitch 3 µm	X / Y calibration, orthogonality	On request
M1807	AFM pitch grating, 2D	Pitch 10 µm	X / Y calibration, orthogonality	On request
M1808	AFM step height	20 nm steps	Z calibration	On request
M1809	AFM step height	100 nm steps	Z calibration	On request
M1810	AFM step height	500 nm steps	Z calibration	On request
M1811	AFM tip check sample	Sharp nano-features	Tip shape and wear assessment	On request

Specifications are typical values; every lot ships with a Certificate of Conformance, and measured data are available on request. Prices on request.